



**Waseda University**

Research Institute for Science and Engineering

# **Design of a Clean, High Brightness Light Source for EUV Lithography Research in Shorter Wavelength**

**Research Institute for Science and Engineering,  
Waseda University**

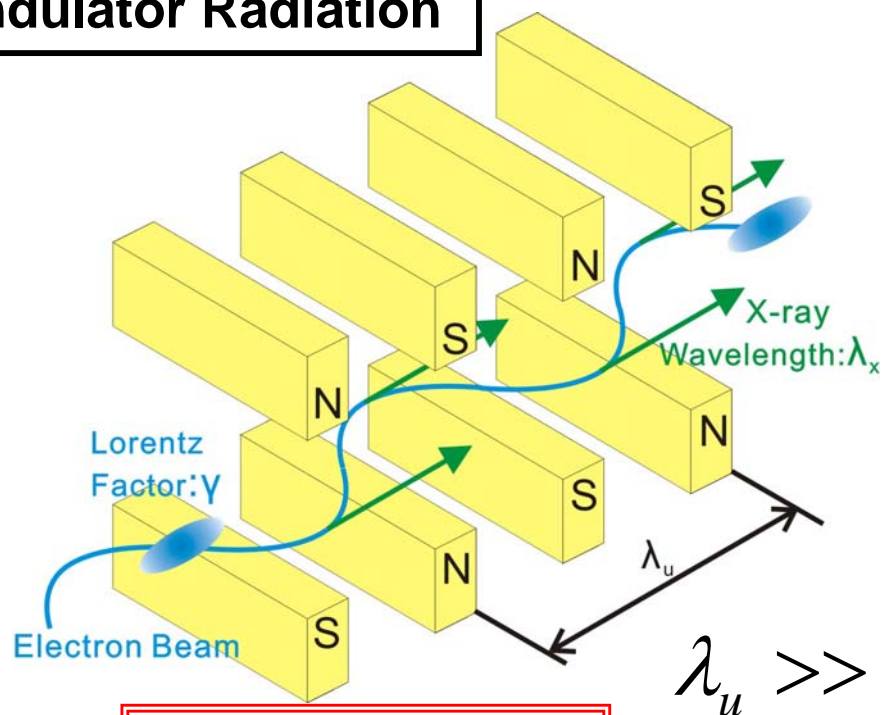
**Kazuyuki Sakaue, Akira Endo, Masakazu Washio**

- **Laser Compton Scattering**
- **Soft X-ray Generation at Waseda University**
- **Design of EUV Light Source**
  - **Low Repetition Case**
  - **High Repetition Case**
- **Summary**

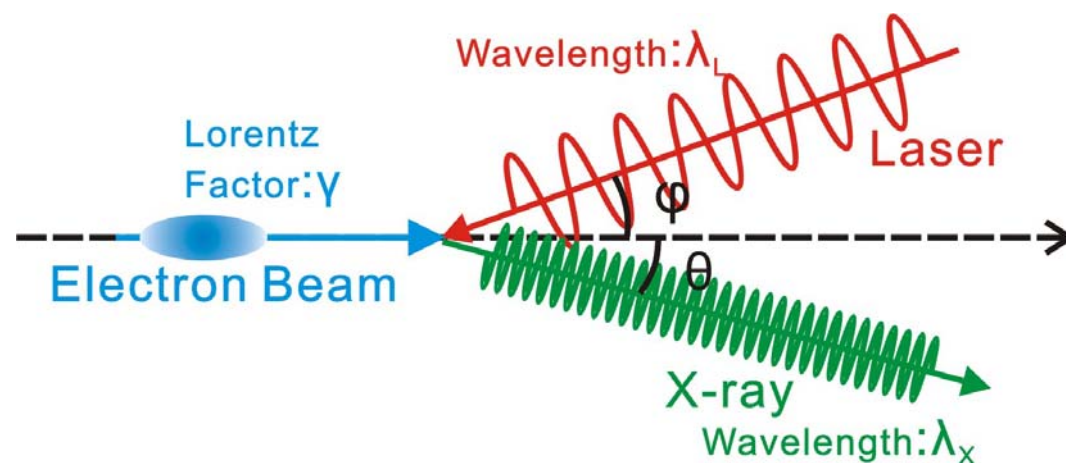
# Laser Compton Scattering

## Comparison of Undulator Radiation and Laser-Compton Scattering

### Undulator Radiation



### Laser-Compton Scattering



$$E_X = 2\gamma^2 \cdot hc / \lambda_u$$

$$E_X = 2\gamma^2 \cdot hc / (\lambda_L / (\cos \phi + 1 / \beta))$$

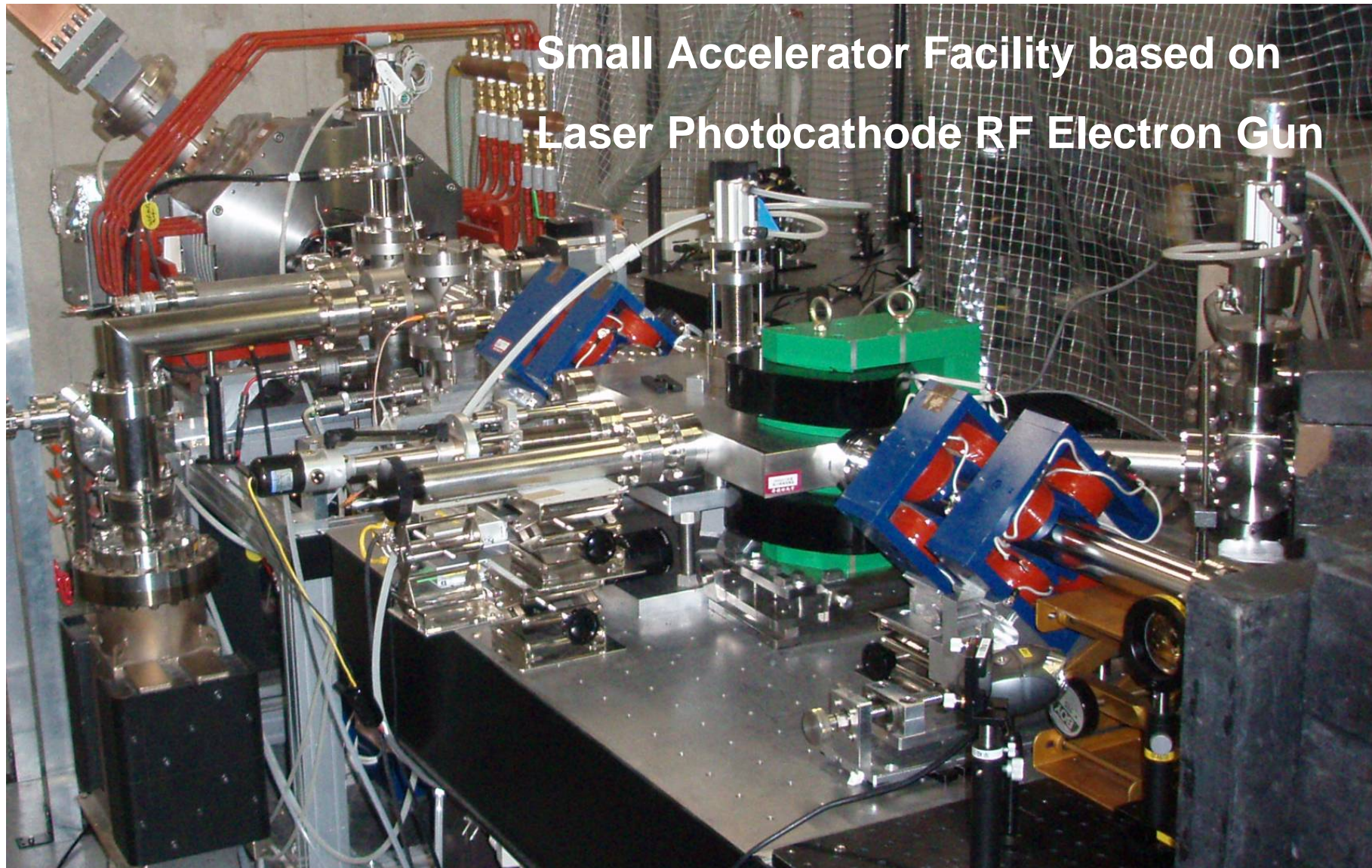
Undulation period can be shortened  
over 3-order of magnitude

High energy photon is  
produced with small  
accelerator system



# Soft X-ray Generation Experiment

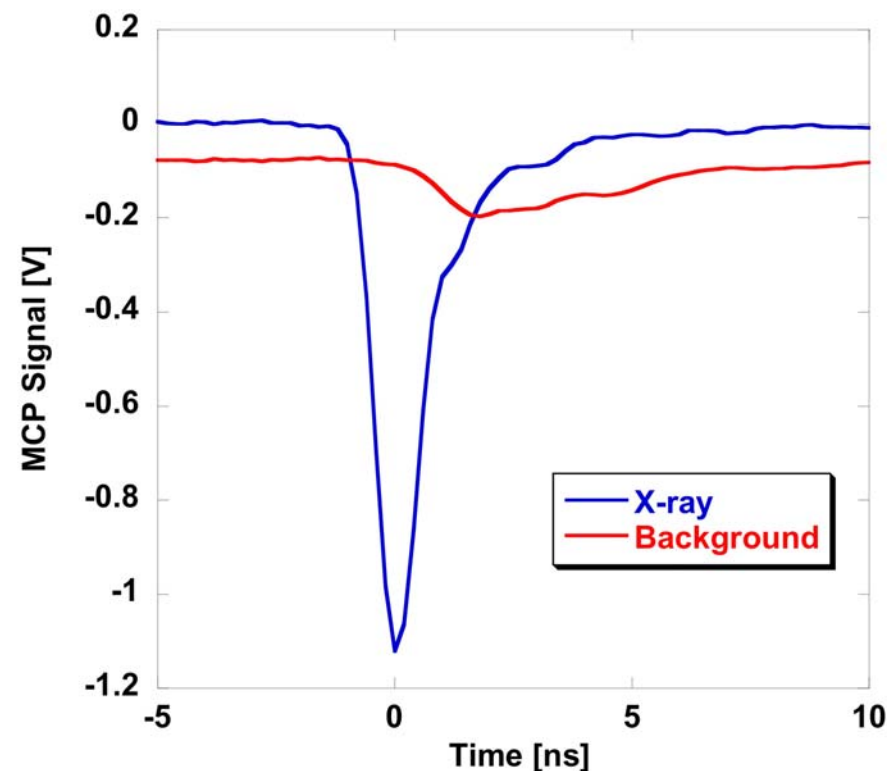
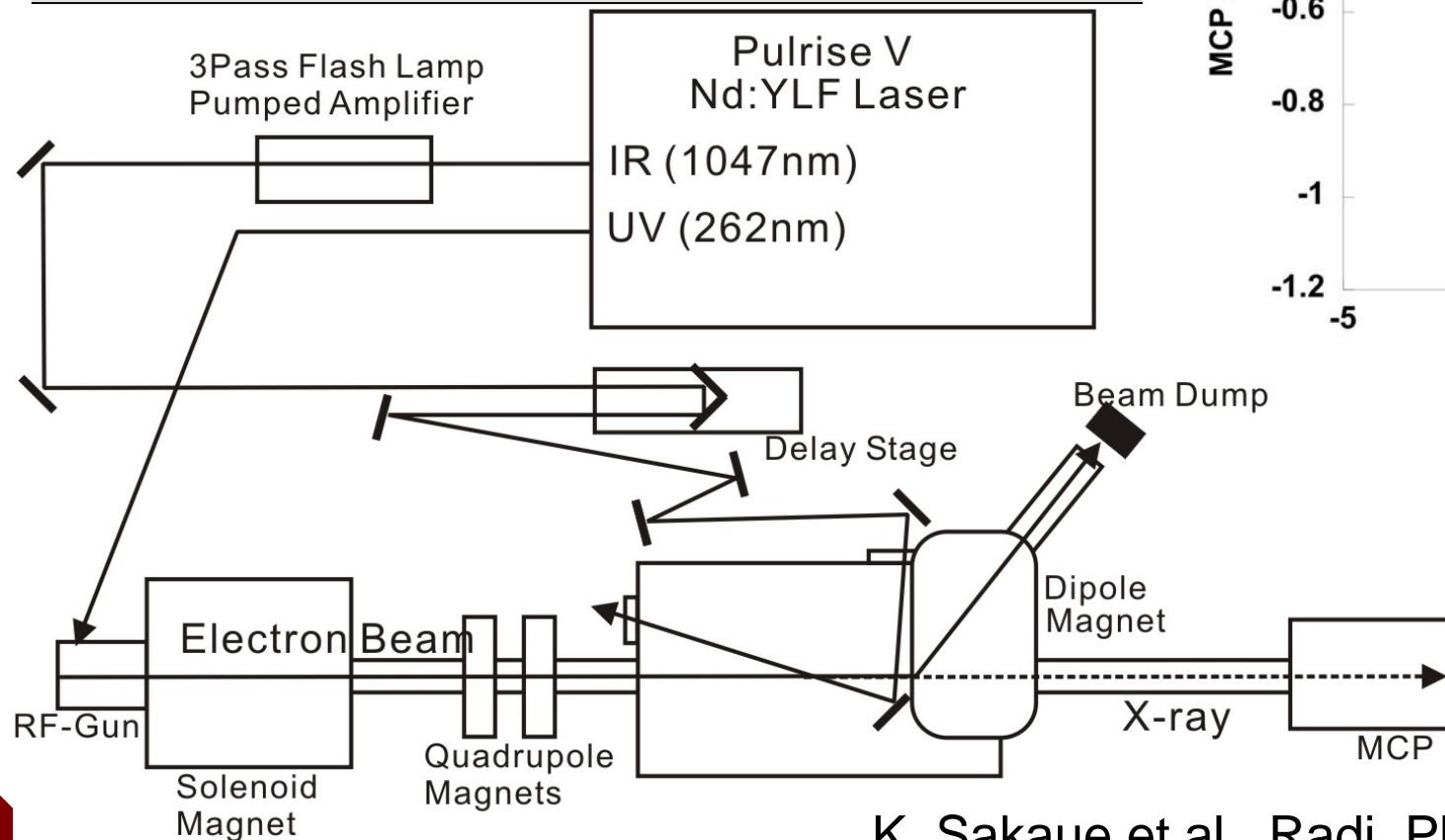
## Facility Outlook at Waseda University



# Soft X-ray Generation Experiment

## Results of Soft X-ray Generation

Electron beam		Laser beam	
Energy	4.6 MeV	Wavelength	1047 nm
Bunch charge	350 pC	Pulse energy	36 mJ
Size (horizontal)	251 $\mu\text{m}$	Size (horizontal)	42 $\mu\text{m}$
Size (vertical)	56 $\mu\text{m}$	Size (vertical)	42 $\mu\text{m}$
Bunch length	10 ps (FWHM)	Pulse duration	10 ps (FWHM)



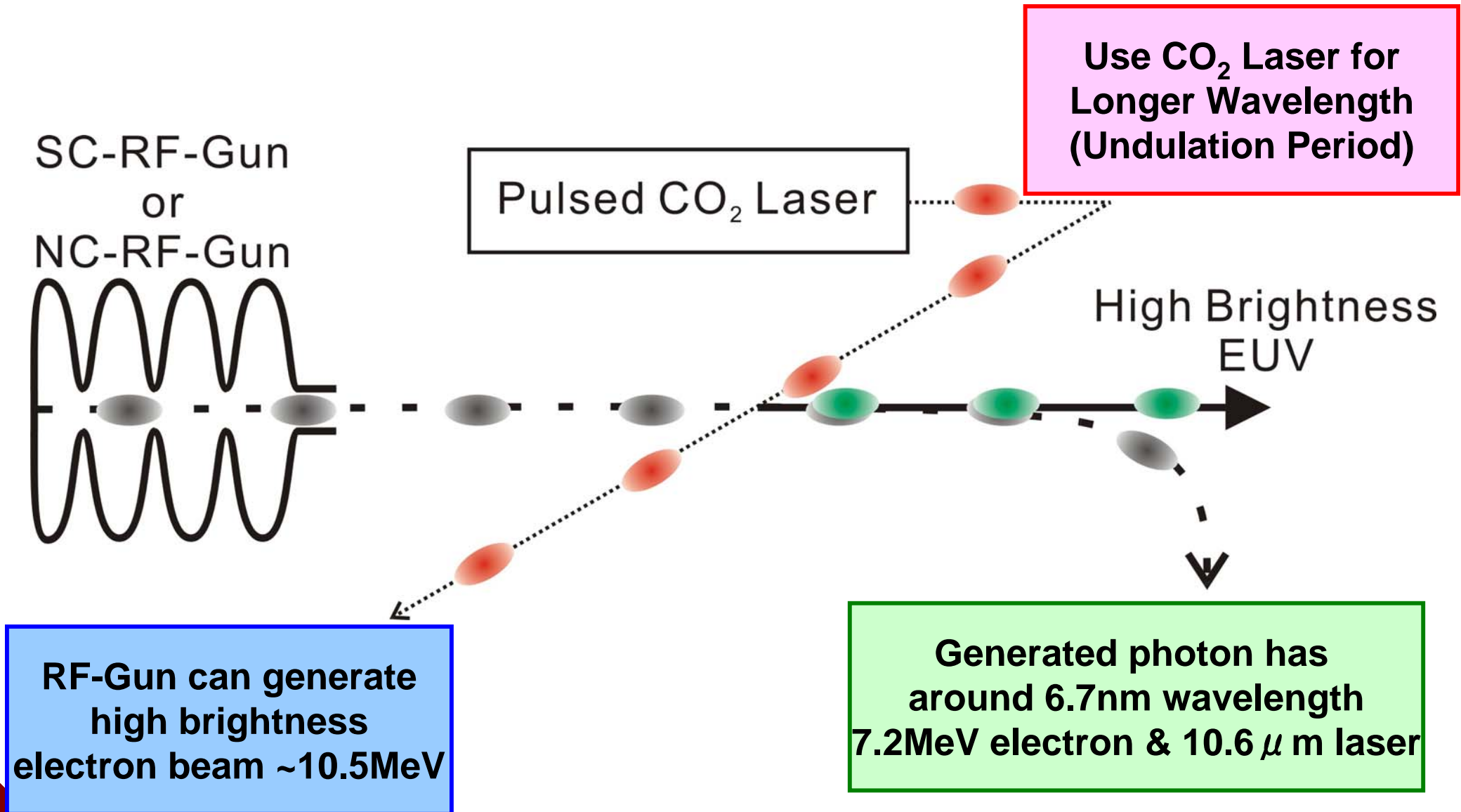
$3.3 \times 10^4$  Photons  
were produced  
in 1 pulse  
Ex~420eV (2.8nm)

K. Sakaue et al., Radi. Phys. Chem. 77(2008)1134



# Design of EUV Light Source

## Design of EUV Light Source based on Laser-Compton Scattering



# Design of EUV Light Source

We have 2 case of designs

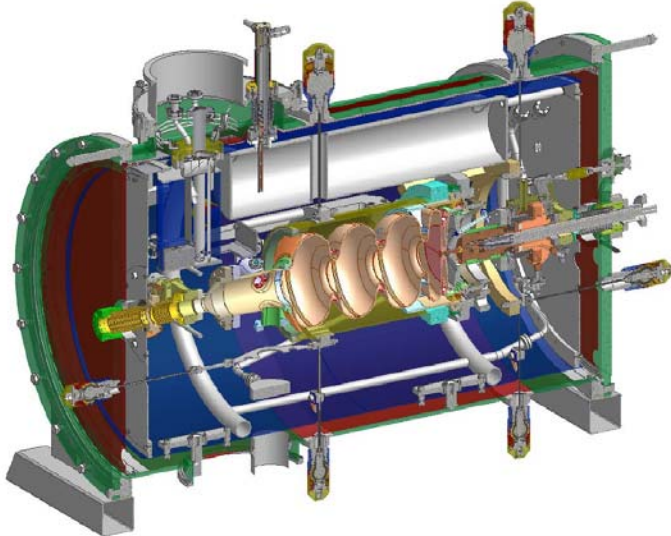
“Low Rep. Case (100kHz)” and “High Rep. Case (100MHz)”

	100kHz	100MHz	Electron Beam
Bunch charge	1nC/bunch	77pC/bunch	
Bunch length	3psec (rms)	3psec	
Pulse energy	1J/pulse	20 $\mu$ J/pulse	Laser
Pulse duration	20nsec	20psec	
Enhancement	None	5000	
Diameter	10 $\mu$ m	20 $\mu$ m	EUV
Colliding angle	0deg	5deg	
EUV power	12.8 $\mu$ W/2%b	1mW/2%bw	

# EUV Light Source (Low Rep. Case)

## Components of Low Rep. Case

### Electron Accelerator



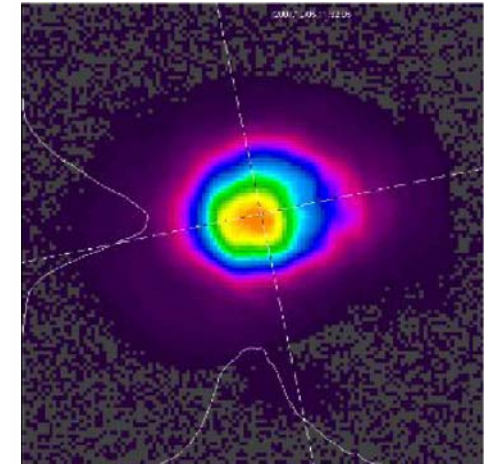
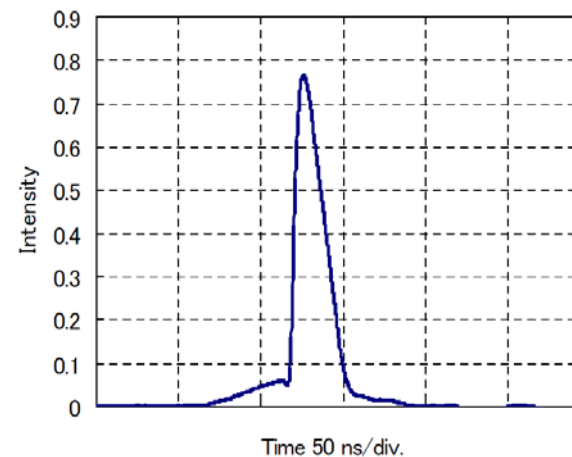
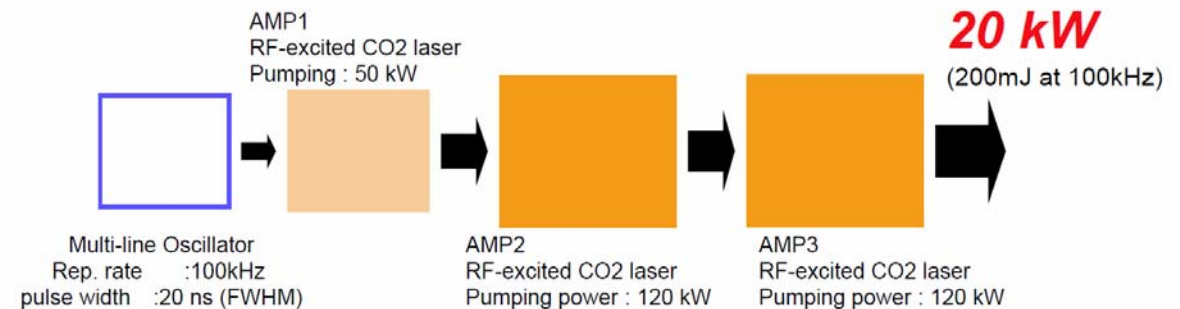
SC-RF-Gun (Teichert et al., FEL08)



NC-RF-Gun (Now under testing at KEK)



### CO<sub>2</sub> Laser



1J/pulse is also feasible technology



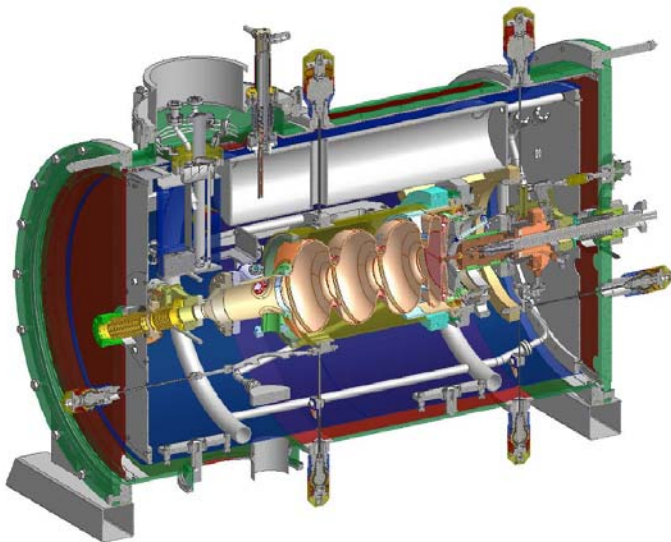
# EUV Light Source (High Rep. Case)

## Components of High Rep. Case (Electron Beam)

>Almost same requirements with ERL (Energy Recovery Linac)  
electron source

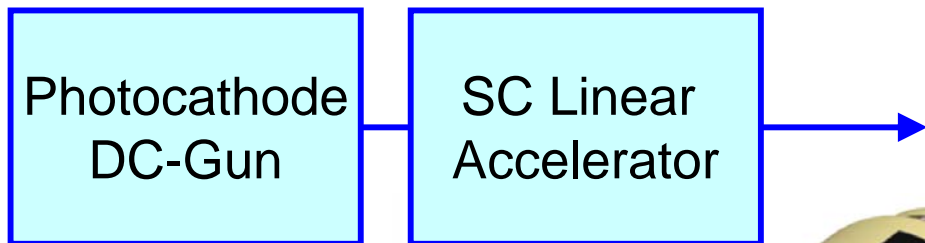
These will be mature in near future

### SC-RF-Gun



SC-RF-Gun (Teichert et al., FEL08)

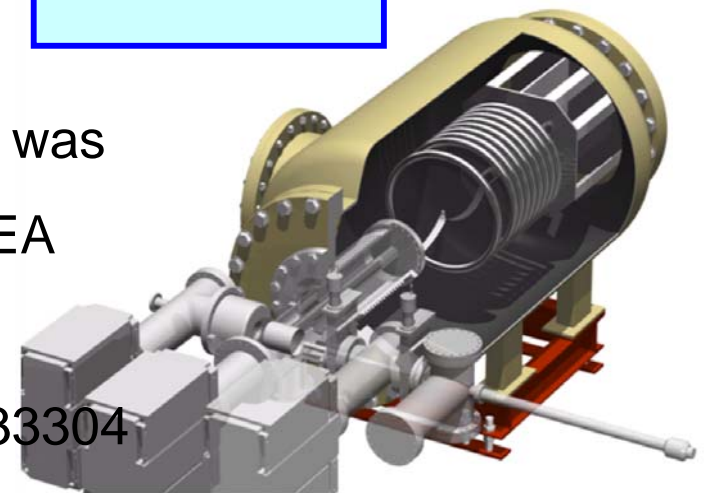
### DC-Gun & SC Linac



500kV DC-Gun was  
achieved at JAEA

R. Nagai et al.,

RSI 81(2010)033304

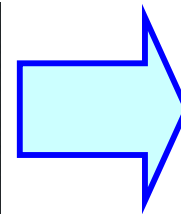
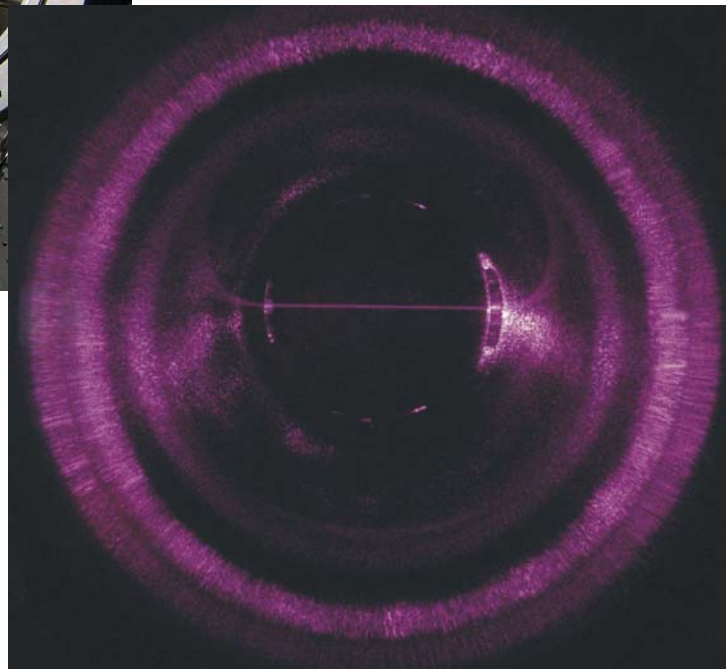
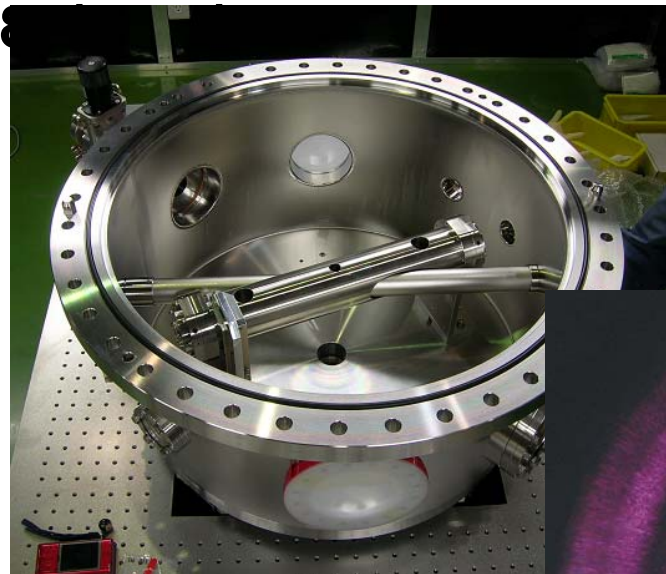


# EUV Light Source (High Rep. Case)

## Components of High Rep. Case (Laser Beam)

>Need to use Super-cavity technology

Demonstrated at  $1\ \mu\text{m}$  wavelength K. Sakaue et al., RSI



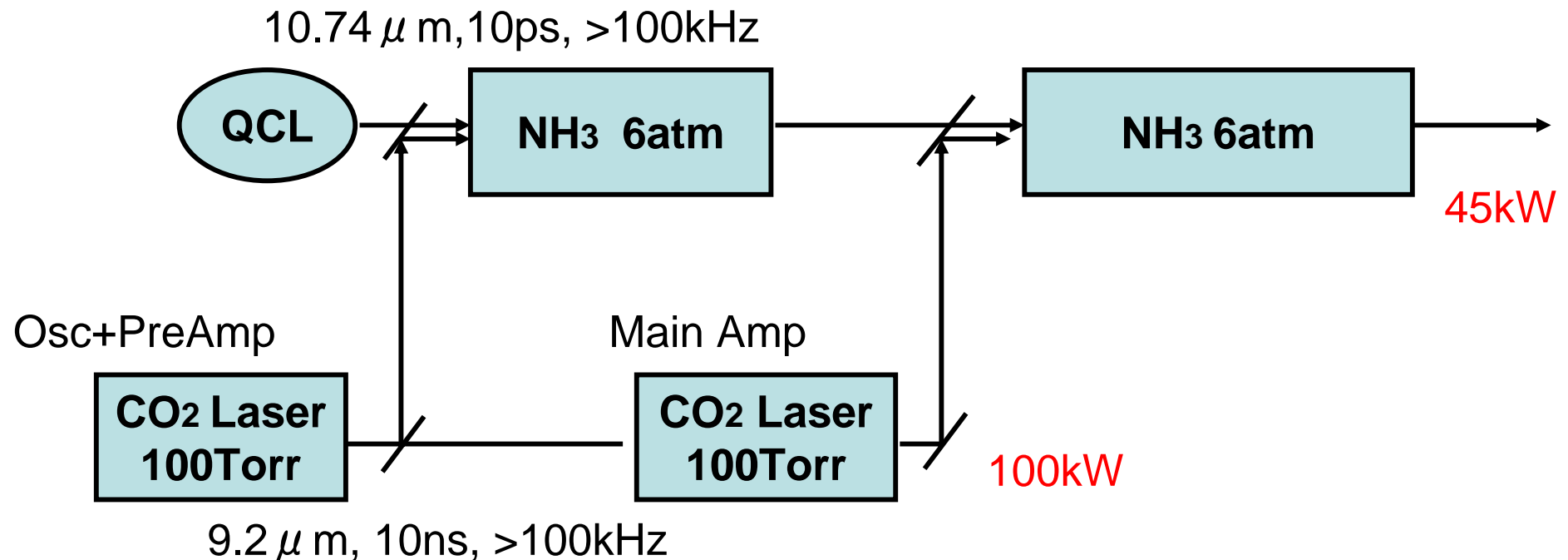
Need to R&D at  $10.6\ \mu\text{m}$  CO<sub>2</sub> laser storage in optical super-cavity with enhancement of 5000

In our calculation, 600enhancement will be achieved with commercial mirrors

# EUV Light Source (High Rep. Case)

## Components of High Rep. Case (Laser Beam)

>Need to demonstrate high rep., short pulsed CO<sub>2</sub> laser



20psec pulsed CO<sub>2</sub> laser will be achievable using optically pumped NH<sub>3</sub>  
J. D. White et al., IEEE J. QE, 29(1993)201

# Summary

We have been developing a laser-Compton scattering  
Soft X-ray was demonstrated by 4.6MeV electron and 1 $\mu$ m laser

Under our experiences of laser-Compton scattering,  
we designed 2 types of EUV light source

## <Low Rep. Case (100kHz)>

SC(NC)-RF-Gun and CO<sub>2</sub> laser will generate  
10  $\mu$ W/2%b.w. EUV (6.7nm)

## <High Rep. Case (100MHz)>

SC-RF-Gun (or DC-Gun+SC Linac) and CO<sub>2</sub> laser with Super-cavity  
1mW/2%b.w. EUV (6.7nm) under R&Ds

